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JAN 06 2009

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Kazuyoshi Okawa, et al.

Serial No.: 10/588,636

Filing Date: August 4, 2006

Title: Semiconductor Device Test  
Apparatus and Method

Conf. No. 9797

Examiner: Daniel F. McMahon

Art Unit: 2117

January 6, 2009  
San Francisco, California

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**REQUEST FOR EXTENSION OF TIME**

Applicants request a two-month extension of time in which to submit this Response to Office Action. This extension extends the deadline for submission until January 6, 2009. You are authorized to charge the \$490 extension fee plus any additional fee that may be due to deposit account 07-0137.



David N. Lathrop

**RESPONSE TO OFFICE ACTION**

Sir:

This communication is submitted in response to the office action mailed August 6, 2008 (referred to herein as "Office Action").